


<b>Search Notes</b>  	<b>Application/Control No.</b>  10784979	<b>Applicant(s)/Patent Under Reexamination</b>  YACH ET AL.
	<b>Examiner</b>  Lin, Shew-Fen	<b>Art Unit</b>  2166

### SEARCHED

Class	Subclass	Date	Examiner
455	412.2 and associated text search	1/5/08	SFL
455	412.2 with text search	1/25/10	SFL
707	102	1/25/10	SFL
707	758	4/1/10	SFL

### SEARCH NOTES

Search Notes	Date	Examiner
East	8/3/07	SFL
NPL (google)	8/3/07	SFL
East	1/5/08, 1/8/08, 1/9/08	SFL
East text search	7/20/08	SFL
East text search	12/10/08	SFL
East text search	5/15/09	SFL
East text search	1/25/10	SFL
NPL (google, ACM, IEEE)	1/25/10	SFL
East text refresh search	4/1/10	SFL
	4/1/10	SFL

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
455	412.2	1/25/10	SFL
707	104.1	1/25/10	SFL
455	412.2	4/1/10	SFL
707	999.102	4/1/10	SFL
707	781-784	4/1/10	SFL

--	--